### 1. General description

PNP high-voltage low V<sub>CEsat</sub> Breakthrough In Small Signal (BISS) transistor in a medium power SOT223 (SC-73) Surface-Mounted Device (SMD) plastic package.

#### 2. Features and benefits

- High voltage
- Low collector-emitter saturation voltage V<sub>CEsat</sub>
- High collector current capability I<sub>C</sub>
- High collector current gain h<sub>FE</sub> at high I<sub>C</sub>
- AEC-Q101 qualified

### 3. Applications

- · Electronic ballast for fluorescent lighting
- LED driver for LED chain module
- LCD backlighting
- HID front lighting
- Automotive motor management
- Hook switch for wired telecom
- Switch Mode Power Supply (SMPS)

#### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>CEO</sub>	collector-emitter voltage	open base	-	-	-600	V
I <sub>C</sub>	collector current		-	-	-0.1	Α
h <sub>FE</sub>	DC current gain	$V_{CE}$ = -10 V; $I_{C}$ = -10 mA; $T_{amb}$ = 25 °C	70	130	-	





600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

## 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	В	base	4	2, 4
2	С	collector		1—
3	E	emitter		. M
4	С	collector	⊟1 ⊟2 ⊟3 SC-73 (SOT223)	3 sym028

## 6. Ordering information

Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
PBHV3160Z	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223		

### 7. Marking

Table 4. Marking codes

Type number	Marking code
PBHV3160Z	HV316Z

600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

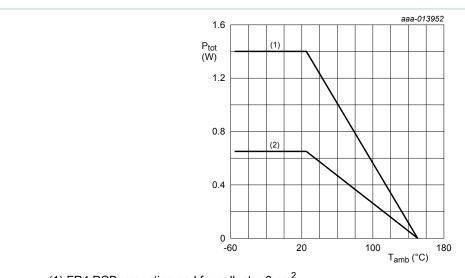
### 8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{CBO}$	collector-base voltage	open emitter		-	-600	V
$V_{CEO}$	collector-emitter voltage	open base		-	-600	V
V <sub>CESM</sub>	collector-emitter peak voltage	V <sub>BE</sub> = 0 V		-	-600	V
V <sub>EBO</sub>	emitter-base voltage	open collector		-	-6	V
I <sub>C</sub>	collector current			-	-0.1	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> ≤ 25 °C	[1]	-	0.65	W
			[2]	-	1.4	W
Tj	junction temperature			-	150	°C
T <sub>amb</sub>	ambient temperature			-55	150	°C
T <sub>stg</sub>	storage temperature			-65	150	°C

- [1] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.



- (1) FR4 PCB, mounting pad for collector 6 cm<sup>2</sup>
- (2) FR4 PCB, standard footprint

Fig. 1. Power derating curves

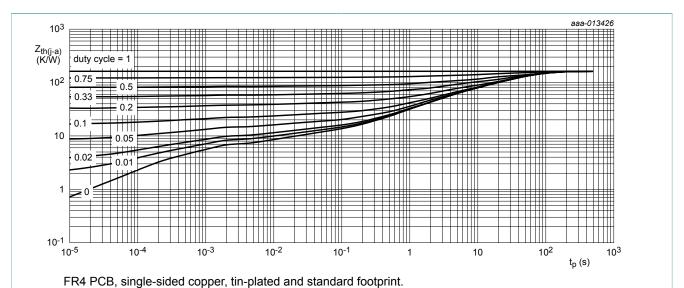
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#### Thermal characteristics

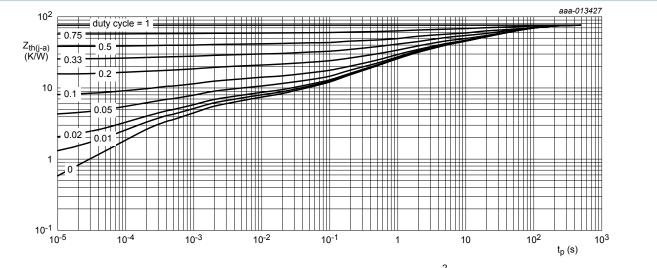
Thermal characteristics Table 6.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	[1]	-	-	190	K/W
			<u>[2]</u>	-	-	89	K/W
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point			-	-	20	K/W

- Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.



Transient thermal impedance from junction to ambient as a function of pulse duration; typical values Fig. 2.



FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.

PBHV3160Z

Fig. 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

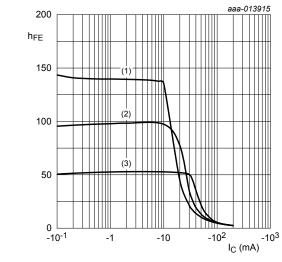
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#### 600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

#### 10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$I_{CBO}$	collector-base cut-off	$V_{CB}$ = -400 V; $I_E$ = 0 A; $T_{amb}$ = 25 °C	-	-	-100	nA
	current	$V_{CB}$ = -400 V; $I_{E}$ = 0 A; $T_{j}$ = 150 °C	-	-	-10	μA
I <sub>CES</sub>	collector-emitter cut-off current	$V_{CE} = -400 \text{ V}; V_{BE} = 0 \text{ V}; T_{amb} = 25 \text{ °C}$	-	-	-100	nA
I <sub>EBO</sub>	emitter-base cut-off current	$V_{EB} = -5 \text{ V}; I_{C} = 0 \text{ A}; T_{amb} = 25 \text{ °C}$	-	-	-100	nA
h <sub>FE</sub>	DC current gain	$V_{CE}$ = -10 V; $I_{C}$ = -10 mA; $T_{amb}$ = 25 °C	70	130	-	
V <sub>CEsat</sub>	collector-emitter saturation voltage	$I_C$ = -30 mA; $I_B$ = -6 mA; $T_{amb}$ = 25 °C	-	-150	-250	mV
V <sub>BEsat</sub>	base-emitter saturation voltage	$I_C$ = -50 mA; $I_B$ = -5 mA; pulsed; $t_p \le 300 \ \mu s; \ \delta \le 0.02; \ T_{amb} = 25 \ ^{\circ}C$	-	-	-950	mV
f <sub>T</sub>	transition frequency	$V_{CE}$ = -10 V; $I_{C}$ = -5 mA; f = 100 MHz	-	38	-	MHz
C <sub>c</sub>	collector capacitance	$V_{CB}$ = -20 V; $I_{E}$ = 0 A; $i_{e}$ = 0 A; f = 1 MHz; $T_{amb}$ = 25 °C	-	6	-	pF
C <sub>e</sub>	emitter capacitance	$V_{EB}$ = -0.5 V; $I_{C}$ = 0 A; $i_{c}$ = 0 A; $f_{c}$ = 1 MHz; $f_{amb}$ = 25 °C	-	76	-	pF



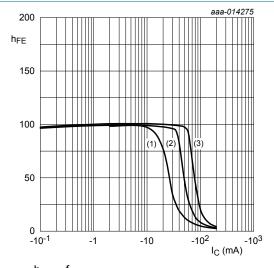
 $V_{CE} = -10 \text{ V}$ 

(1)  $T_{amb} = 100 \, ^{\circ}C$ 

(2)  $T_{amb}$  = 25 °C

(3)  $T_{amb} = -55 \, ^{\circ}C$ 

Fig. 4. DC current gain as a function of collector current; typical values



 $h_{FE} = f_{(IC)}$ 

 $T_{amb}$  = 25 °C

(1)  $V_{CE} = -10 \text{ V}$ 

(2)  $V_{CE} = -25 \text{ V}$ 

(3)  $V_{CE} = -50 \text{ V}$ 

Fig. 5. DC current gain as a function of collector current; typical values

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#### 600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

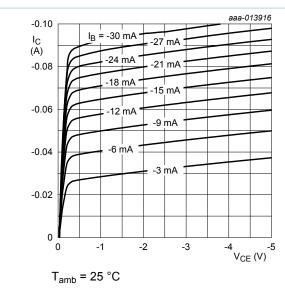
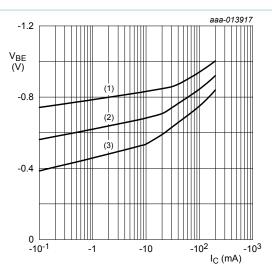


Fig. 6. Collector current as a function of collectoremitter voltage; typical values



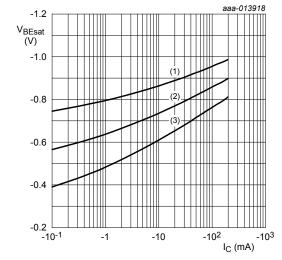
$$V_{CE} = -10 \text{ V}$$

(1) 
$$T_{amb} = -55 \, ^{\circ}C$$

(2) 
$$T_{amb} = 25 \, ^{\circ}C$$

(3) 
$$T_{amb} = 100 \, ^{\circ}C$$

Fig. 7. Base-emitter voltage as a function of collector current; typical values



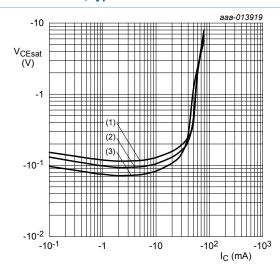
$$I_C/I_B = 5$$

(1) 
$$T_{amb} = -55 \, ^{\circ}C$$

(2) 
$$T_{amb}$$
 = 25 °C

(3) 
$$T_{amb} = 100 \, ^{\circ}C$$

Fig. 8. Base-emitter saturation voltage as a function of collector current; typical values



$$I_C/I_B = 5$$

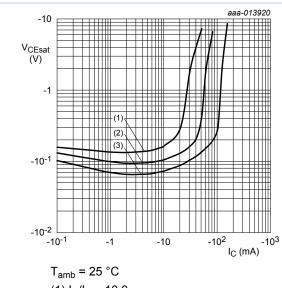
(1) 
$$T_{amb} = 100 \, ^{\circ}C$$

(2) 
$$T_{amb}$$
 = 25 °C

(3) 
$$T_{amb} = -55 \, ^{\circ}C$$

g. 9. Collector-emitter saturation voltage as a function of collector current; typical values

#### 600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

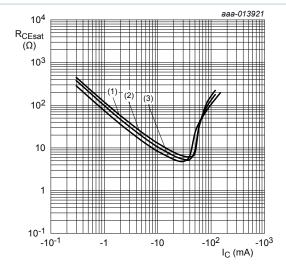


(1) 
$$I_C/I_B = 10.0$$

(2) 
$$I_C/I_B = 5.0$$

(3) 
$$I_C/I_B = 2.5$$

Fig. 10. Collector-emitter saturation voltage as a function of collector current; typical values



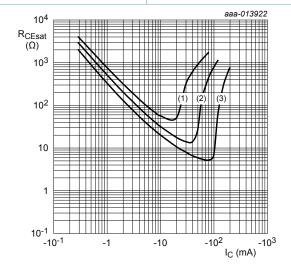
$$I_{\rm C}/I_{\rm B} = 5$$

(1) 
$$T_{amb} = 100 \, ^{\circ}C$$

(2) 
$$T_{amb} = 25 \, ^{\circ}C$$

(3) 
$$T_{amb} = -55 \, ^{\circ}C$$

Fig. 11. Collector-emitter saturation resistance as a function of collector current; typical values



$$T_{amb} = 25 \, ^{\circ}C$$

(1) 
$$I_C/I_B = 10.0$$

(2) 
$$I_C/I_B = 5.0$$

(3) 
$$I_C/I_B = 2.5$$

Fig. 12. Collector-emitter saturation resistance as a function of collector current; typical values

### 11. Test information

PBHV3160Z

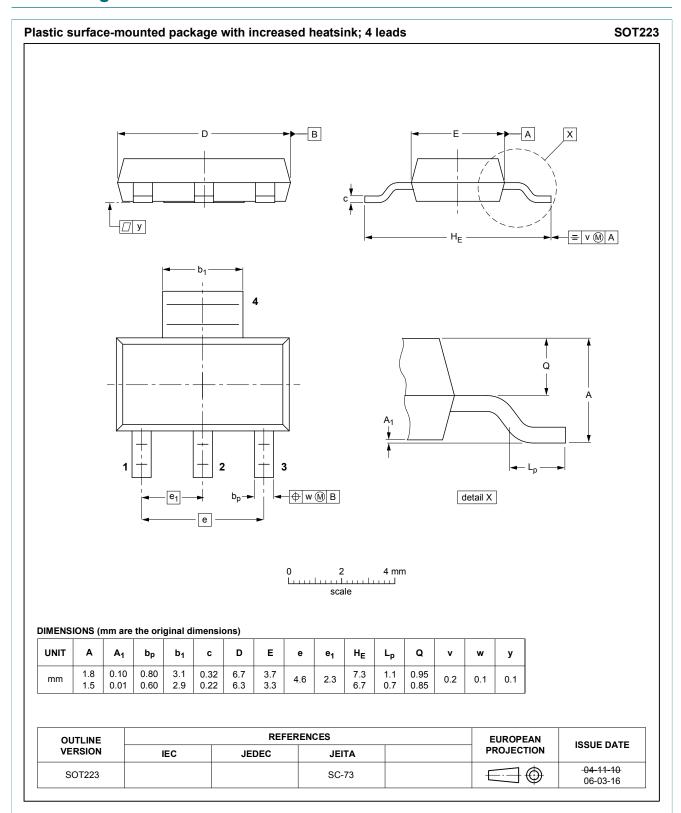
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### 11.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard Q101 - Stress test qualification for discrete semiconductors, and is suitable for use in automotive applications.

#### 600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

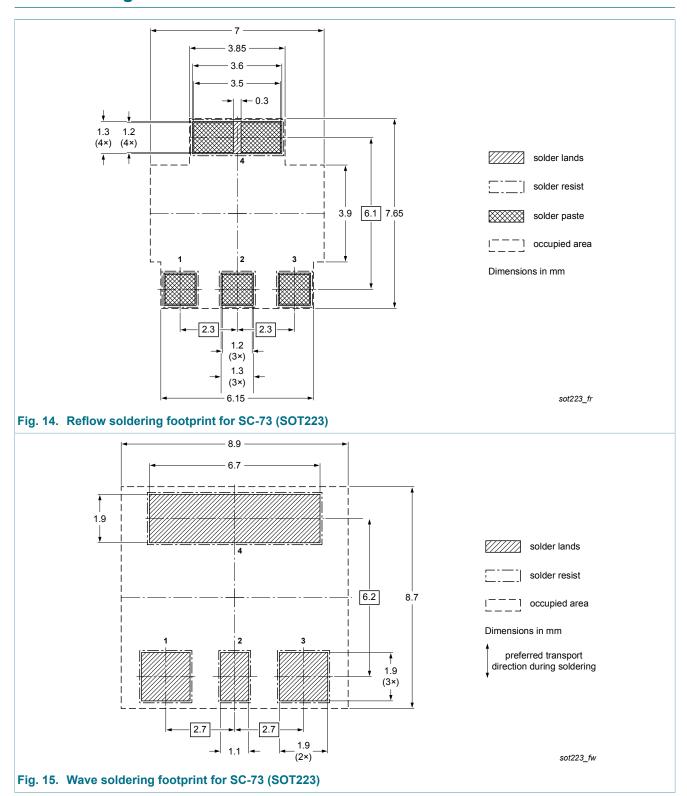
### 12. Package outline



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### 13. Soldering



600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

## 14. Revision history

#### Table 8. Revision history

Data sheet ID	Release date	Data sheet status	Change notice	Supersedes
PBHV3160Z v.1	20140818	Product data sheet	-	-

#### 600 V, 0.1 A PNP high-voltage low VCEsat (BISS) transistor

### 15. Legal information

#### 15.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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